# APPROVAL SHEET

 Customer
 Name
 :

 Customer
 P/N
 :

 Frequency
 : 25.000000
 MHz

 Aker Approved P/N : CXAN-025000-5-D4-00

 Aker MPN
 : CXAN-025000-5-D4-00

 Rev.
 : 1

 ISSUE DATE
 : Feb.8.2023

APPROVED	CHECKED	PREPARED				
Tin		Hank				
APPROVED BY CUSTOMER						

# AKER TECHNOLOGY CO., LTD.

ADDRESS: NO 11-3, Jianguo Rd., Tanzi Dist., Taichung City 427, Taiwan.

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Web: www.aker.com.tw MSL:Level 1

**RoHS** compliant



11KC1 11pp10 (Cd 1/1) . C11111 023000 3 D+ 0	Aker Approved P/N:	CXAN-025000-5-D4-0
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APPROVED: Tin SHEET: 1 of 9

PREPARED : Hank REV. : 1

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Rev.	Date	Reviser	Revise contents
1	2023/2/8	Hank	Initial Released
i			



Aker Approved P/N	:	CXAN-0250	000-5-D4-00
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#### SMD CRYSTAL SPECIFICATION

## 1. ELECTRICAL CHARACTERISTICS

■ Standard atmospheric conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurement and tests are as follow:

Ambient temperature: 25±5°C

Relative humidity : 40%~70%

If there is any doubt about the results, measurement shall be made within the following limits:

Ambient temperature: 25±3°C

Relative humidity : 40%~70%

■ AKER Model: CXA-531

■ Oscillation Mode: Fundamental

■ Cutting Mode : AT CUT

■ Measurement Equipment : 250B(Measured FL)

■ Insulation Resistance: More than 500M ohms at DC 100V

		Electrical Spec				
Parameters	Symbol	Min.	Тур.	Max.	Units.	Notes
Nominal Frequency	FL	2	5.00000	0	MHz	
Frequency Tolerance		±30		ppm	at 25°C ± 3°C	
Frequency Stability		±50		ppm	Operating Temp (Refer 25°ℂ)	
Load Capacitance	CL	18		pF		
Aging			±3		ppm	First Year
Operating Temperature		-20	~	70	$^{\circ}\!\mathbb{C}$	
Storage Temperature Range		-55	~	125	$^{\circ}\!\mathbb{C}$	
Drive Level	DL			100	uW	
Equivalent Series Resistance	ESR			50	Ω	@ Series
Shunt Capacitance	C0			5	pF	

<sup>\*</sup>Please kindly be noted that AKER DO NOT guarantee parts quality which involves human security application.\*



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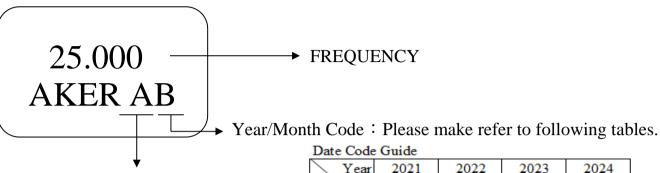
**APPROVED** SHEET:  $3 \overline{\text{ of } 9}$ Tin

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(Unit:mm)

#### 2. MARKING:



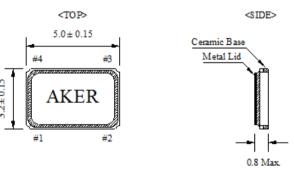
Internal identification code

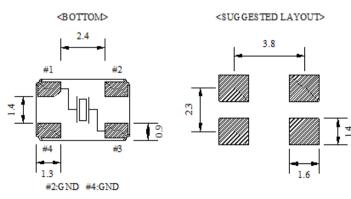
Date Code Guide

Year	2021	2022	2023	2024
	2025	2026	2027	2028
Month	(4N+1)	(4N+2)	(4N+3)	(4N+0)
JAN	a	n	Α	N
FEB	b	p	В	P
Mar	С	q	C	Q
Apr	d	r	D	R
May	e	S	E	S
Jun	f	t	F	T
Jul	g	u	G	U
Aug	h	v	H	V
Sep	j	w	J	W
Oct	k	X	K	X
Nov	1	y	L	Y
Dec	m	Z	M	Z
	_			

A cycle every four years

#### 3. DIMENSION:

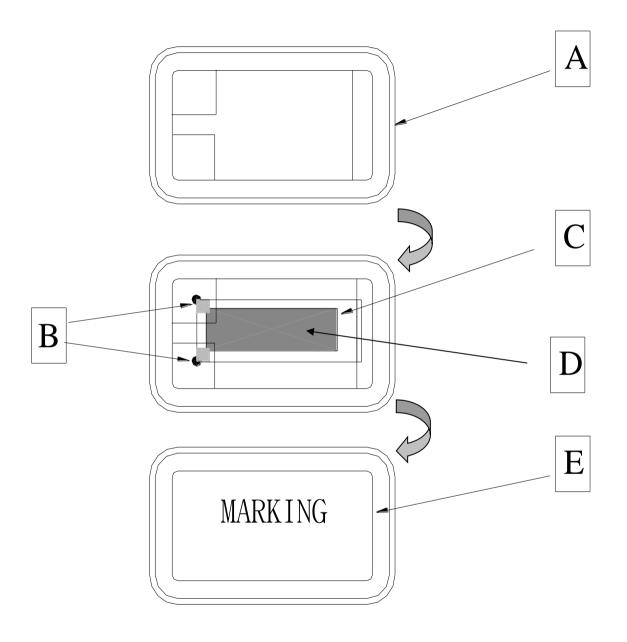






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# 4. STRUCTURE ILLUSTRATION



COMPONENTS MATERIA		MATERIALS	CO	MPONENTS	MATERIALS
A	Base (Package)	Ceramic(Al <sub>2</sub> O <sub>3</sub> )+Kovar(Fe/Co/Ni)	D	Electrode	Cr / Ag
В	Conductive adhesive	Ag / Silicon resin	Е	Lid	Fe/Co/Ni
С	Crystal blank	SiO <sub>2</sub>			

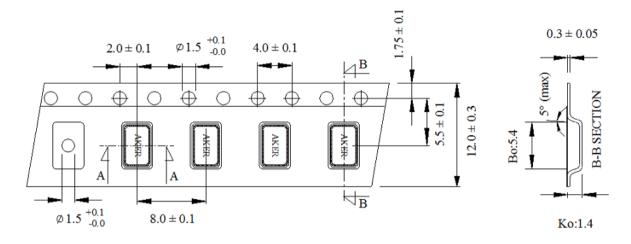


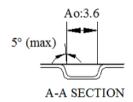
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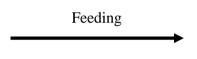
#### 5. PACKING:

#### TAPE SPECIFICATION

(Unit:mm)

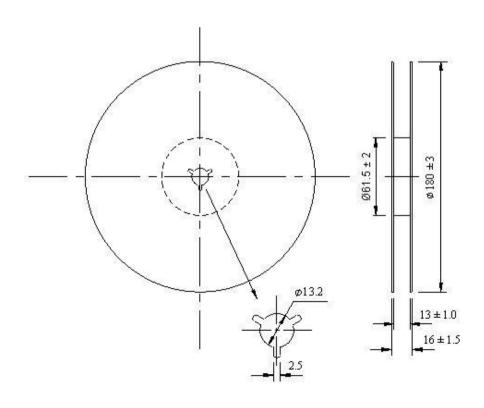






#### **OUTLINE DIMENSION**

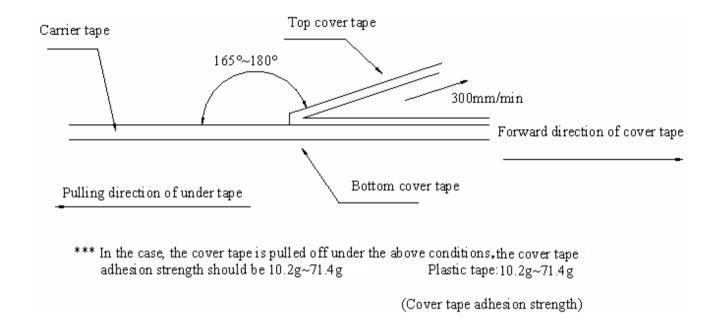
(Unit:mm)



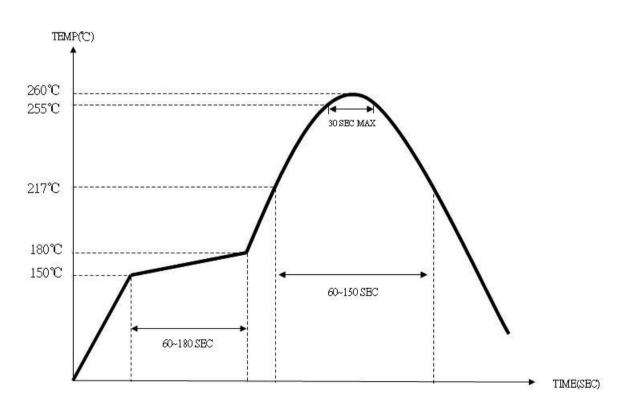


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#### 6. COVER TAPE ADHESION STRENGTH:



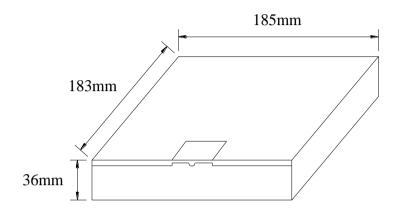
## 7. SOLDERING REFLOW PROFILE

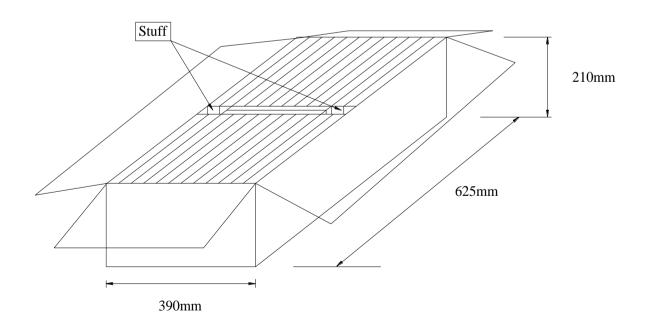




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# 8. PACKING:





SMD product packs 32 BOX = The outside box packs ( 1000 PCS \* 32 BOX = 32000 PCS )(MAX)



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#### 9. MECHANICAL PERFORMANCE

7. WIECIMIN	ICAL PERFORMANCE	
TEST ITEMS	TEST METHODS AND TEST CONDITION	PERFORMANCE
9.1 Drop Test	The specimen is measured for its frequency and resistance before the test. It is then dropped from a hight of 75 cm or more as a free fall object onto a hard wooden plate of 30mm or more in thickness.  ( in accordance with JIS-C0044 )	
9.2 Vibration Test	The specimen is measured for its frequency and resistance before the test. Most them into X,Y and Z axes, respectively, for the vibration test. Vibration condition:  Frequency range; 20 ~ 2000HZ  Peak to peak amplitude: 1.52 mm  Peak acceleration: 20G  Sweep time: 20 minute / axis  Pendicular total test time: 4 hours	To satisfy the electrical performance.
9.3 Resistance to Soldering Test	( in accordance with MIL-STD-883F: 2007.3 )  The specimen is measured for its frequency and resistance before the test. Place the specimen on the belt of the converynace and let it pass through the reflow with the presetted temperature condition.  After passing twice the reflow place, the specimen under the referee condition for -~2 hours and then measure its electrical performance.  Temperature Condition of IR Simulation:  The temperature range of the preheated section is setted at 150 ~ 180°C for 60~120 sec. For the next section the temperature range is setted at 217~260°C for 45~90 sec. and within this time range the specimen should be able to sustain at the peak temperature, 260+/-3°C , for 10 sec long.  ( in accordance with JESD22-B106-B )	
9.4 Fine Leak Test	Place the specimen in a pressurized container and pressurize it with the detection gas ( mixed gas consisting of 95% or more helium ) for at least 2 hours. Complete the measurement of the concentration of helium within 30 min after taking it out from the pressurized container.  ( in accordance with MIL-STD-883F: 1014.11 )  The referee condition.  Temperature $25 \pm 2 \degree C$ Humidity $44 \degree 55 \%$ Pressure $86 \degree 106 \text{ kPa}$ ( in accordance with MIL-STD-883E: 1014. 9 )	Less than 1.0 * 10 <sup>-8</sup> atm .c.c. / sec, Helium



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# 10. CLIMATIC RESISTANCE

TU. CLIMAT	IC RESISTANCE	
TEST ITEMS	TEST METHODS AND TEST CONDITION	PERFORMANCE
10.1 Low Temp Exposure Test	The specimen is measured for its frequency and resistance before the test . Place the specimen in the chamber and kept it at the temperature of - $40 \pm 3^{\circ}$ C for $168 \pm 6$ hours . Take the specimen out of the chamber and measure itselectrical performance after leaving 1 $^{\sim}$ 2 hours under the referee condition. ( in accordance with JIS-C0020 )	
10.2 Aging Test	The specimen is measured for its frequency and resistance before the test . Place the specimen in the testing chamber and keep it at the temperature of $+125 \pm 3^{\circ}$ C for $720 \pm 48$ hours. And then take the specimen out of the chamber and measure its electrical performance after leaving for $1^{\circ}$ 2 hours under the referee condition . ( in accordance with JIS-C0021 )	To satisfy the electrical performance .
10.3 High Temperature & High Humidty	The specimen is measured for its frequency and resistance before the test . Place the specimen in the testing chamber and kept it at the temperature of $+85 \pm 5$ °C and humidity of $85 \pm 5$ % for $168 \pm 6$ hours.and then take the specimen out and measure its electrical performance after leaving for $1^{\sim}$ 2 hours under the referee condition. ( in accordance with MIL-STD-883F: 1004.7 )	
10.4 Temperature Cycle Test	The specimen is measured for its frequency and resistance before the test . Subject the specimen to the 100 cycles of temperature ranges stated below . High temp . + 125 $\pm$ 3 °C (15 $\pm$ 3 min).   Low temp55 $\pm$ 3 °C (15 $\pm$ 3 min).   Measure its electrical performance after leaving it for 1 ~ 2 hours under the referee condition . ( in accordance with MIL-STD-883F : 1010.8 )	